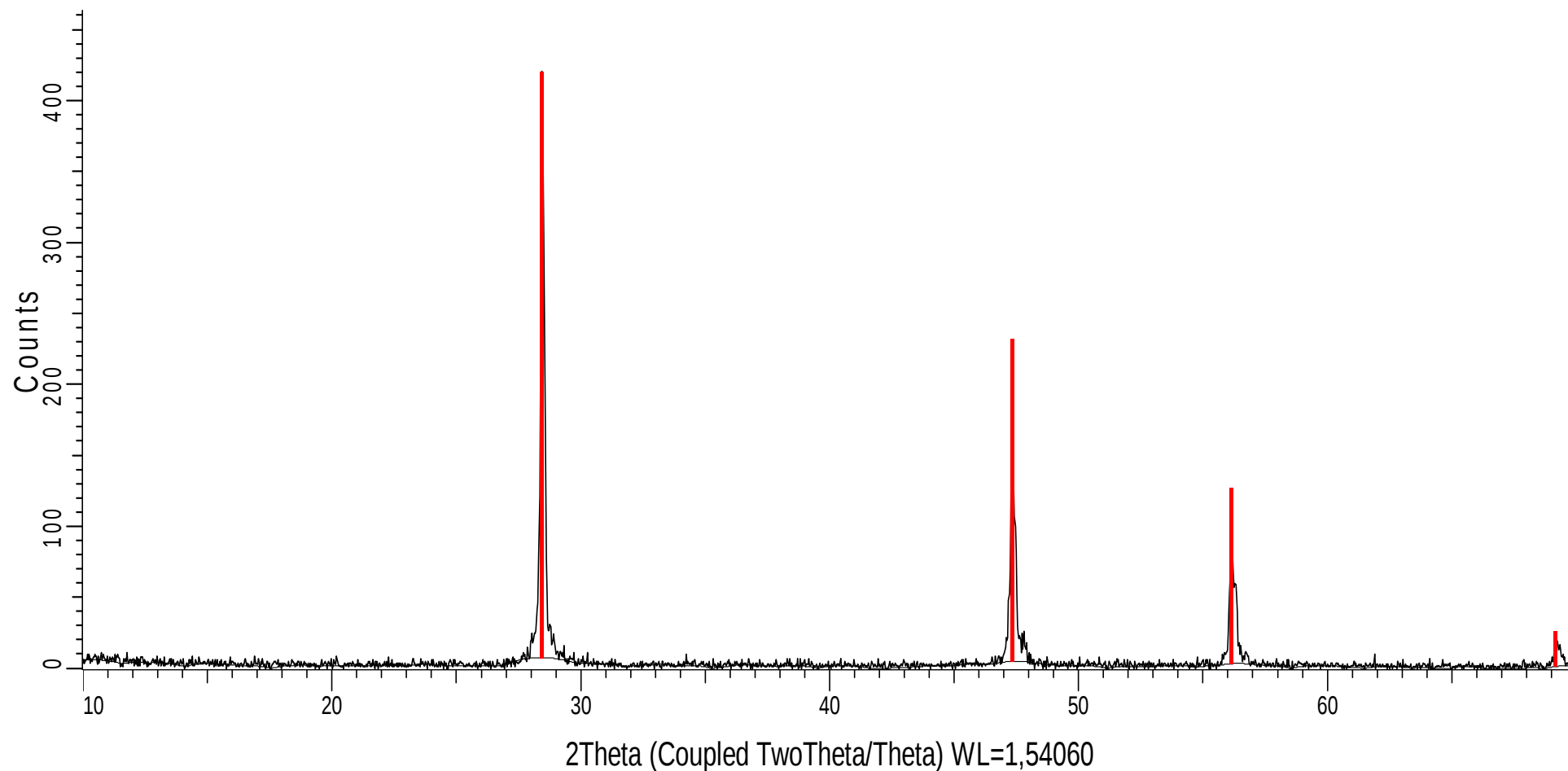


PATRÓN DE SI NIST SRM 640C 24-05-12



 SI NIST XRK900 22-03-12. Barrido tipo Θ - Θ . Rango: 10 a 70 $^{\circ}2\Theta$. Paso: 0,03. Tiempo por paso: 1 seg. Cámara: XRK900 Detector: VANTEC.

 Patrón de SI NIST 640c. Cúbico – a 5.43088 - b 5.43088 - c 5.43088 - α 90.000 - β 90.000 - γ 90.000 – Centrado en las caras – Fd-3m (227) – Z 8 – V 160.181

25 de mayo de 2012

INFORME DE CALIBRACIÓN XRK900

Si NIST 640c D8C 24-05-12

Range Number : 1

R-Values

Rexp : 40.95 Rwp : 43.03 Rp : 30.86 GOF : 1.05
 Rexp` : 50.03    Rwp` : 52.57 Rp` : 40.24 DW : 1.72

Instrument

Primary radius (mm) 200.5
 Secondary radius (mm) 200.5
 Linear PSD 2Th angular range (°) 3
 FDS angle (°) 0.6
 Beam spill, sample length (mm) 14
 Intensity not corrected
 Full Axial Convolution
 Filament length (mm) 12
 Sample length (mm) 14
 Receiving Slit length (mm) 6
 Primary Sollers (°) 2.5
 Secondary Sollers (°) 4

hkl Phase - 1 Le Bail method

Phase name Silicio
 R-Bragg 3.385
 Spacegroup 227
 Cell Mass 0.000
 Cell Volume (Å³) 159.877(81)

Crystallite Size

Cry size Lorentzian (nm) 96(12)
 k: 1 LVol-IB (nm) 61.0(78)
 k: 0.89 LVol-FWHM (nm) 85(11)

Strain

Strain L 0.028(35)
 e0 0.0069(88)

Lattice parameters

a (Å) **NIST 640c Certificate**
 5.42744(92) **5.43311946(92)**

h	k	l	m	d	Th2	I	
1	1	1	8	3.13354	28.46106	3.43	
0	2	2	12	1.91889	47.33505	5.04	
3	1	1	24	1.63644	56.16169	4.6	
2	2	2	8	1.56677	58.89789	0.156	
0	0	4	6	1.35686	69.18082	1.66	

